



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: Mekis et al. GROUP: Unknown
SERIAL NO: Unknown EXAMINER: Unknown
FILED: Herewith
FOR: LOW-LOSS RESONATOR AND METHOD OF MAKING
SAME

Assistant Commissioner of Patents
Washington, D.C. 20231

Sir:

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In compliance with 37 C.F.R. §§1.56, 1.97, and 1.98, Applicant submits
copies of the documents listed on the attached Form PTO-1449.

The Commissioner is authorized to charge Deposit Order Account No. 19-
0079 for any further fee that is required.

Respectfully submitted,

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I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited on
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STATEMENT BY APPLICANT**

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Mekis et al.
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AD						
	AE						
	AF						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
	AG	"Microcavities in photonic crystals: Mode symmetry, tenability, and coupling efficiency", Villeneuve et al., Physical Review B. Volume 54, No. 11, September 15, 1996, The American Physical Society, pgs: 7837-7842
	AH	"Whispering-gallery mode microdisk lasers", McCall et al., Appl. Phys. Lett., January 20, 1992, American Institute of Physics, pgs: 289-291
	AI	"Surface-roughness-induced contradirectional coupling in ring and disk resonators", Little et al., Optics Letters, Vol. 22, No. 1, January 1, 1997; 1997 Optical Society of America; pgs: 4-6
	AJ	"Guided and defect modes in periodic dielectric waveguides", Fan et al., 1995 Optical Society of America, Vol. 12, No. 7, pgs: 1267-1272
	AK	"Air-bridge microcavities", Villeneuve et al., 1995 American Institute of Physics, Appl. Phys. Lett. 67, July 10, 1995, pgs: 167-169
	AL	"Guided Modes in Photonic Crystal Slabs" Physical Review B, Volume 60, No. 8, August 15, 1999, The American Physical Society, pgs: 5751-5758
	AM	"Three-dimensional photon confinement in photonic crystals of low-dimensional periodicity", Villeneuve et al., Vol. 145, No. 6, December 1998, pgs: 384-390
	AN	"Radiation losses of waveguide-based two-dimensional photonic crystals: Positive role of the substrate", Benisty et al., Applied physics Letters, Vol. 76, No. 5, January 31, 2000, pgs 532-534
	AO	"Defect modes of a two-dimensional photonic crystal in an optically thin dielectric slab", Painter et al., 1999 Optical Society of America, Vol. 16, No. 2, February 1999, pgs: 275-285
	AP	"Multiple-cancellation mechanism for high-Q cavities in the absence of a complete photonic band gap", Johnson et al., Applied Physics Letters, Vol. 78, NO. 22, May 28, 2001, pgs: 3388-3390
	AQ	"Ray Chaos and Q Spoiling in Lasing Droplets", Mekis et al., Physical Review Letters, Vol. 75, No. 14, October 2, 1995, The American Physical Society, pgs: 2682-2685
	AR	"High Extraction Efficiency of Spontaneous Emission from Slabs of Photonic Crystals", Fan et al., Physical Review Letters, Vol. 78, No. 17, April 28, 1997, pgs: 3294-3297

EXAMINER

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